

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Iwasaki et al.
Serial No.: Not yet assigned
Filed: herewith
For: CAPACITANCE MEASUREMENT SYSTEM
Art Unit: Not yet assigned
Examiner: Not yet assigned
Confirmation No.: Not yet assigned
Customer No.: 27623
Attorney Docket No.: 40030043-02

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

In accordance with applicants' duty of disclosure under 37 C.F.R. §1.56, please find attached hereto form PTO-1449 listing information which may be material to the patentability of this application, filed concurrently herewith. This Information Disclosure Statement is being filed:

XXX Within three (3) months of the filing date of the national application;

___ Within three (3) months of the date of entry of the national stage as set forth in 37 C.F.R. §1.491 in an international application;

___ Before the mailing date of a first Office Action on the merits;

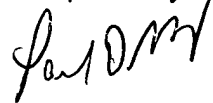
___ After the filing date or date of first Office Action, but before the mailing date of a final action under 37 C.F.R. §1.113, provided that this occurs prior to the issuance of a Notice of Allowance and provided that this I.D.S. is accompanied by either a certification as specified in 37 C.F.R. §1.97(e) or the fee set forth in 37 C.F.R. §1.17(p);

- _____ After the filing date or date of first Office Action, but before the mailing date of a Notice of Allowance under 37 C.F.R. §1.311, provided that this occurs prior to the final action and provided that this I.D.S. is accompanied by either a certification as specified in 37 C.F.R. §1.97(e) or the fee set forth in 37 C.F.R. §1.17(p);
- _____ After the mailing date of a final action under 37 C.F.R. §1.113, provided that this occurs prior to the issuance of a Notice of Allowance and provided that this I.D.S. is accompanied by a certification as specified in 37 C.F.R. §1.97(e) and the fee set forth in 37 C.F.R. §1.17(p); and
- _____ After the mailing date of a Notice of Allowance under 37 C.F.R. §1.311, provided that this occurs prior to or subsequent to the payment of the Issue Fee and provided that this I.D.S. is accompanied by a certification as specified in 37 C.F.R. §1.97(e) and the fee set forth in 37 C.F.R. §1.17(p).
- _____ Filing with RCE Under 37 CFR 1.114.

Cited in the attached PTO-1449 are attached articles entitled, "HP4072A ADVANCED PARAMETRIC TESTER...", "AGILENT 4070 SERIES ACCURATE CAPACITANCE..." and "NEGATIVE -CAPACITANCE EFFECT IN FORWARD-BIASED METAL OXIDE."

It should be understood that attention has been called to the references that have been deemed to be pertinent to the claimed present invention. In concluding what was pertinent, the criteria employed was considered most appropriate in light of the invention shown in the present application. However, the Examiner or others may deem some other criteria to be just as appropriate or more appropriate. Therefore, the Examiner is respectfully urged to review the listed references and to make the usual careful independent search for other prior art that may be pertinent.

Respectfully submitted,



December 2, 2003

Paul D. Greeley
Reg. No. 31,019
Ohlandt, Greeley, Ruggiero & Perle, L.L.P.
One Landmark Square, 10th Floor
Stamford, CT 06901-2682
(203) 327-4500

FORM PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)	Docket Number (Optional)	Application Number
	40030043-02	Not yet assigned
	Applicant	
	Iwaskai et al.	
	Filing Date	Group Art Unit
	herewith	Not yet assigned

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

	Hewlett-Packard Co., "HP4072A Advanced Parametric Tester with HP SPECS," Published in 1999.
	Agilent Technologies, Inc., "Agilent 4070 Series Accurate Capacitance Characterization at the Water Level," Application Note 4070-2, Published in 2000.
	Meiko Matsumura et al., "Negative-Capacitance Effect in Forward-Biased Metal Oxide Semiconductor Tunnel Diodes (MOSTD)," Japan, Vol. 39 (2000), pp. L123-L125, Part 2, No. 2B, February 15, 2000.

EXAMINER	DATE CONSIDERED
----------	-----------------

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP §609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.